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(12) **United States Design Patent**
Morel

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(54) **APPARATUS FOR MEASURING ELECTRICAL PARAMETERS**

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(**) Term: **14 Years**

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(22) Filed: **Jul. 6, 2007**

(30) **Foreign Application Priority Data**

Jan. 19, 2007 (CH) 133588

(51) **LOC (8) Cl.** **10-04**
(52) **U.S. Cl.** **D10/78**
(58) **Field of Classification Search** D10/78; 324/110, 107, 115, 117, 127, 142, 157; 336/175, 336/178, 216
See application file for complete search history.

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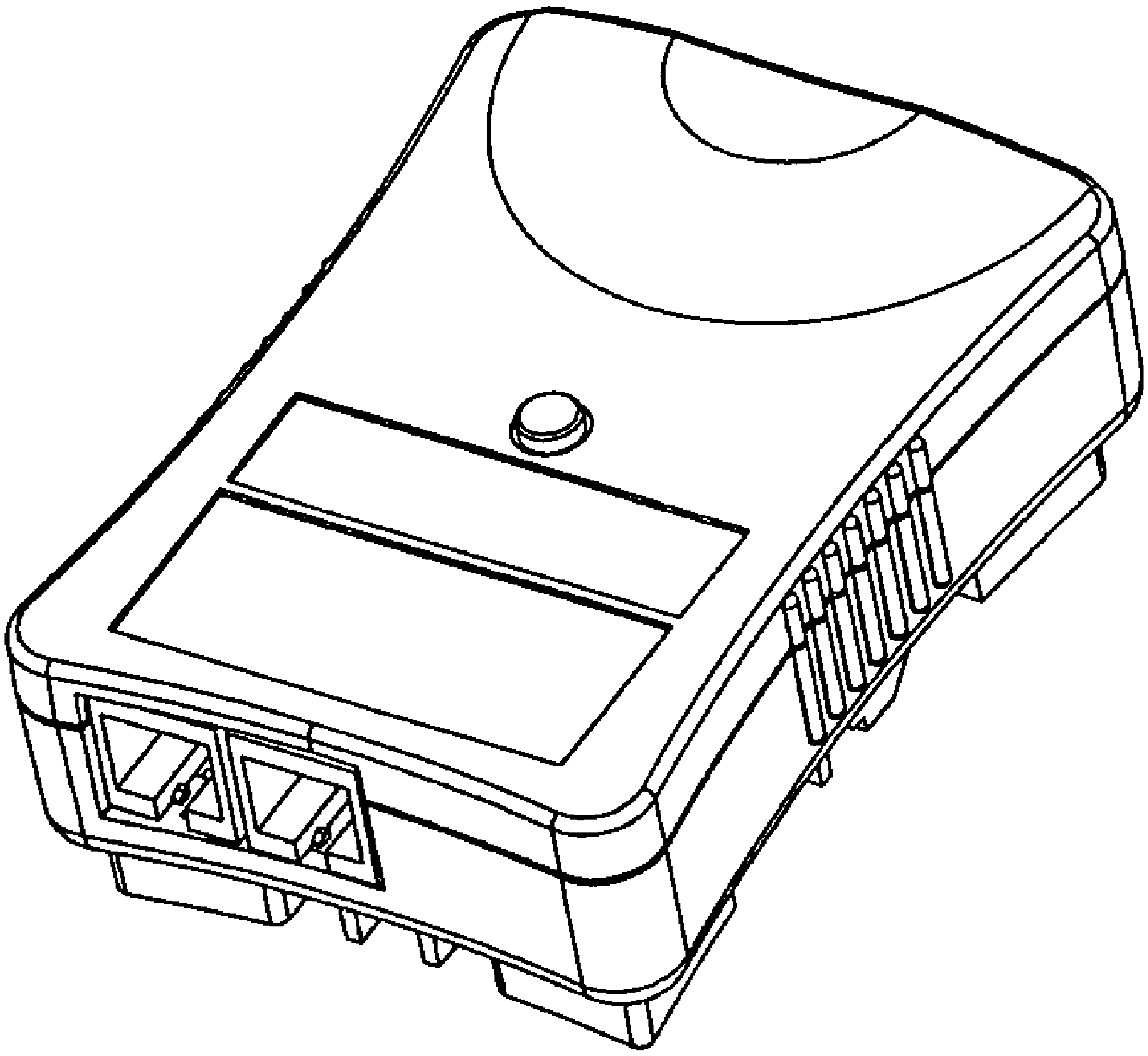
(57) **CLAIM**

The ornamental design for a apparatus for measuring electrical parameters, as shown and described.

DESCRIPTION

FIG. **1** is a top perspective view of the measuring apparatus;
FIG. **2** is a lower perspective view of the apparatus of FIG. **1**;
FIG. **3** is a top plan view of the apparatus of FIGS. **1** and **2**;
FIG. **4** is an end view of the apparatus as depicted in FIG. **3**;
FIG. **5** is a left plan view of the apparatus shown in FIG. **3**;
FIG. **6** is a right plan view of the apparatus shown in FIG. **3**;
FIG. **7** is an end view of the apparatus shown in FIG. **3**; and,
FIG. **8** is a lower plan view of the device shown in FIG. **2**.

1 Claim, 3 Drawing Sheets



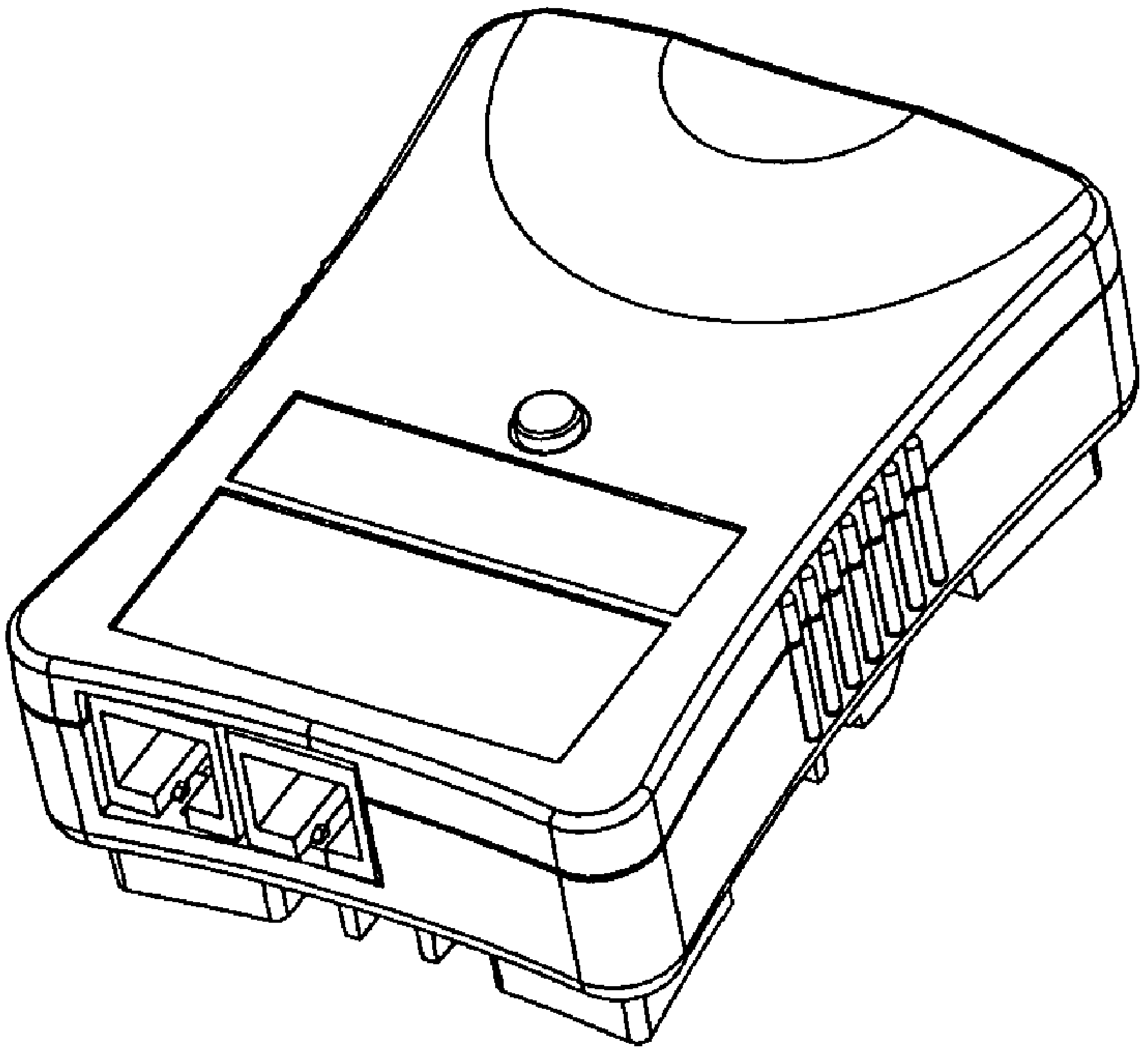


Figure 1

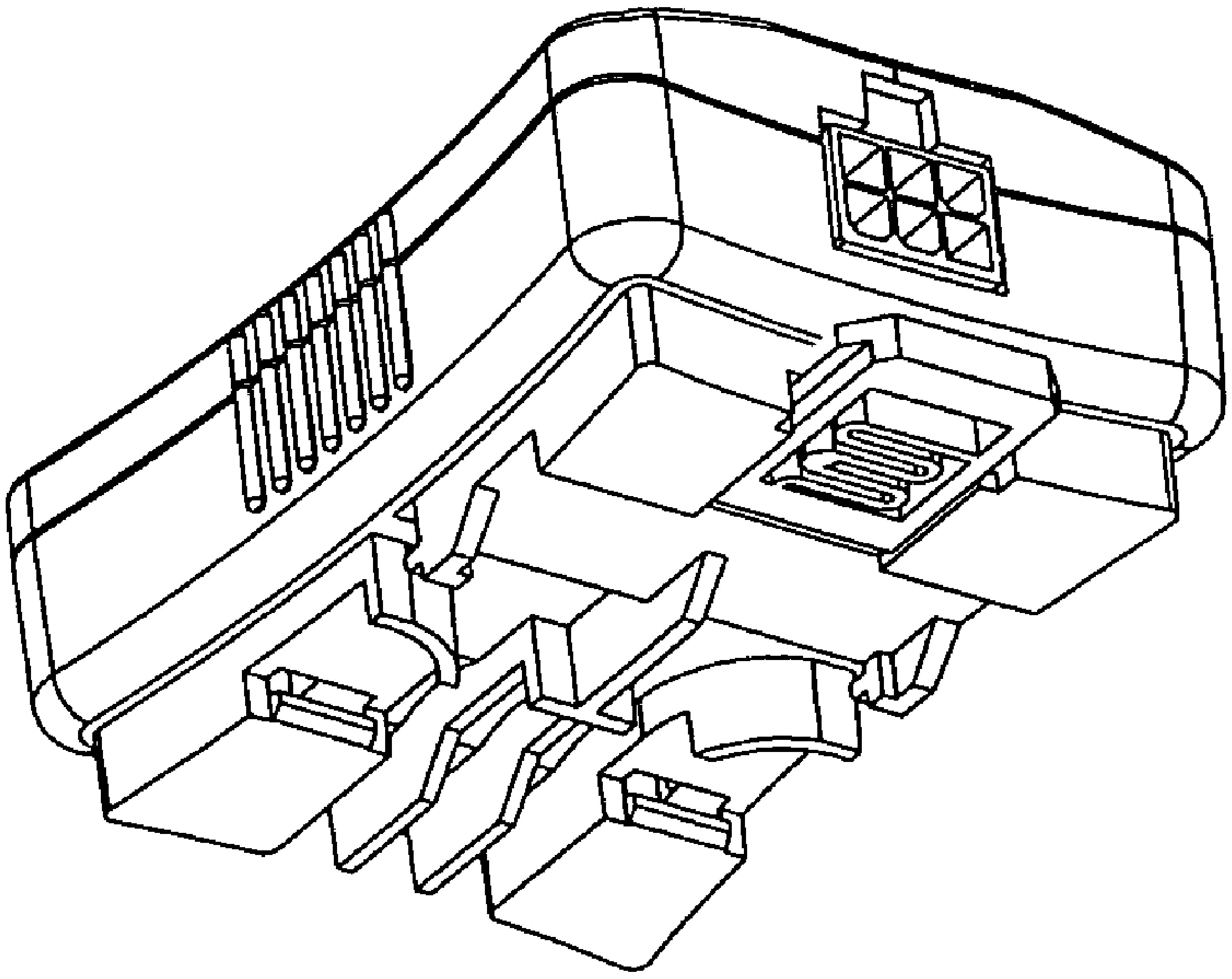


Figure 2

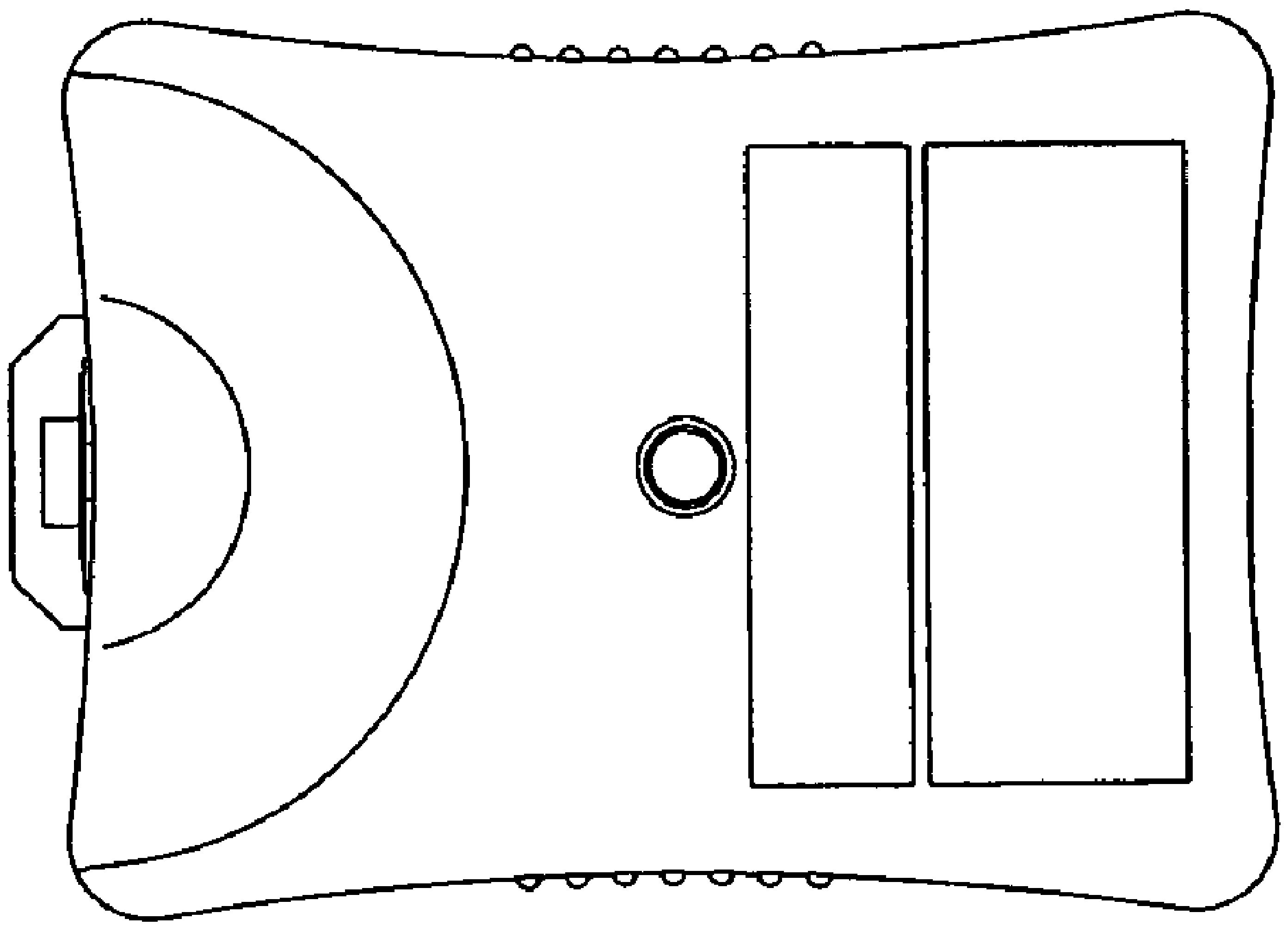


Figure 3

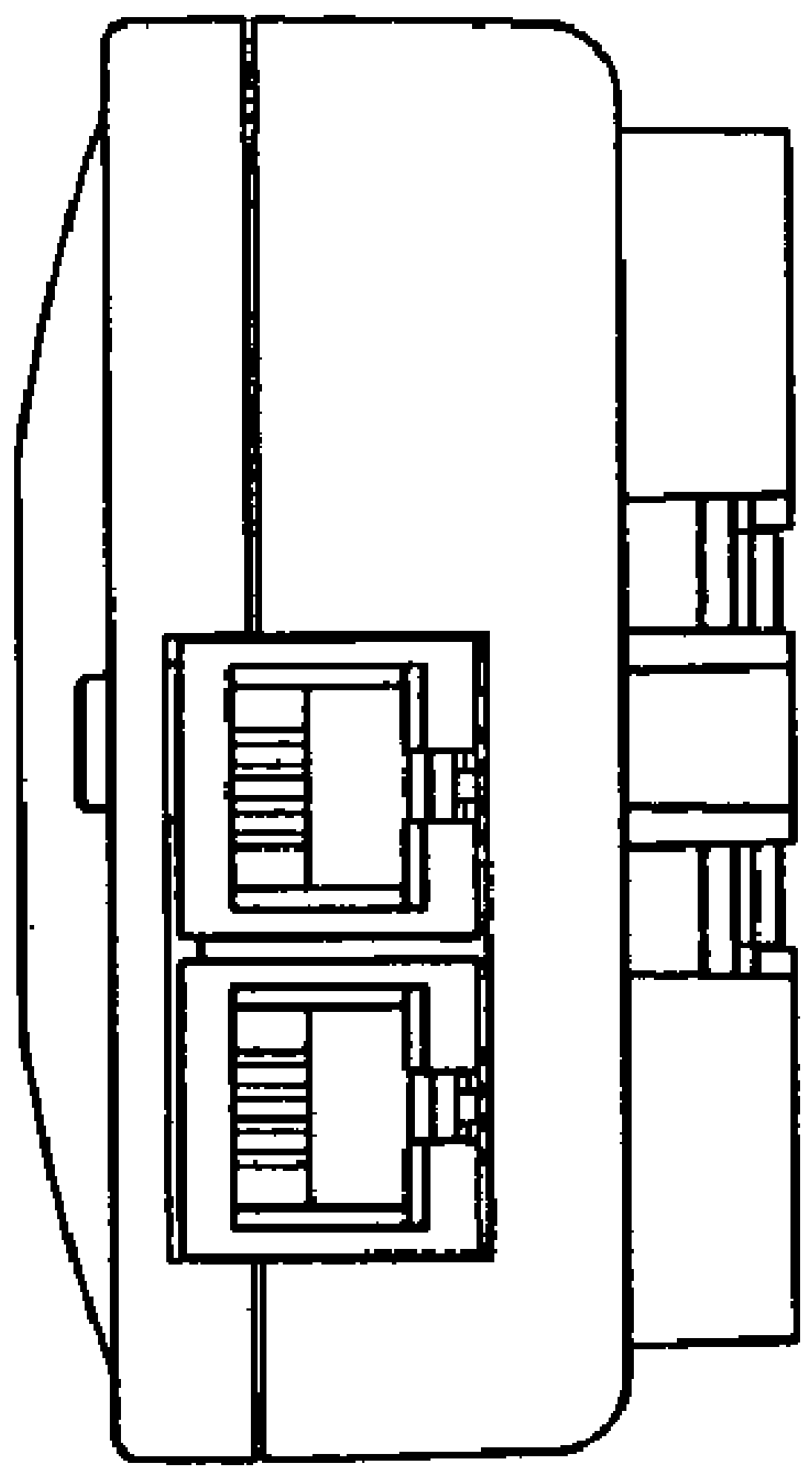


Figure 4

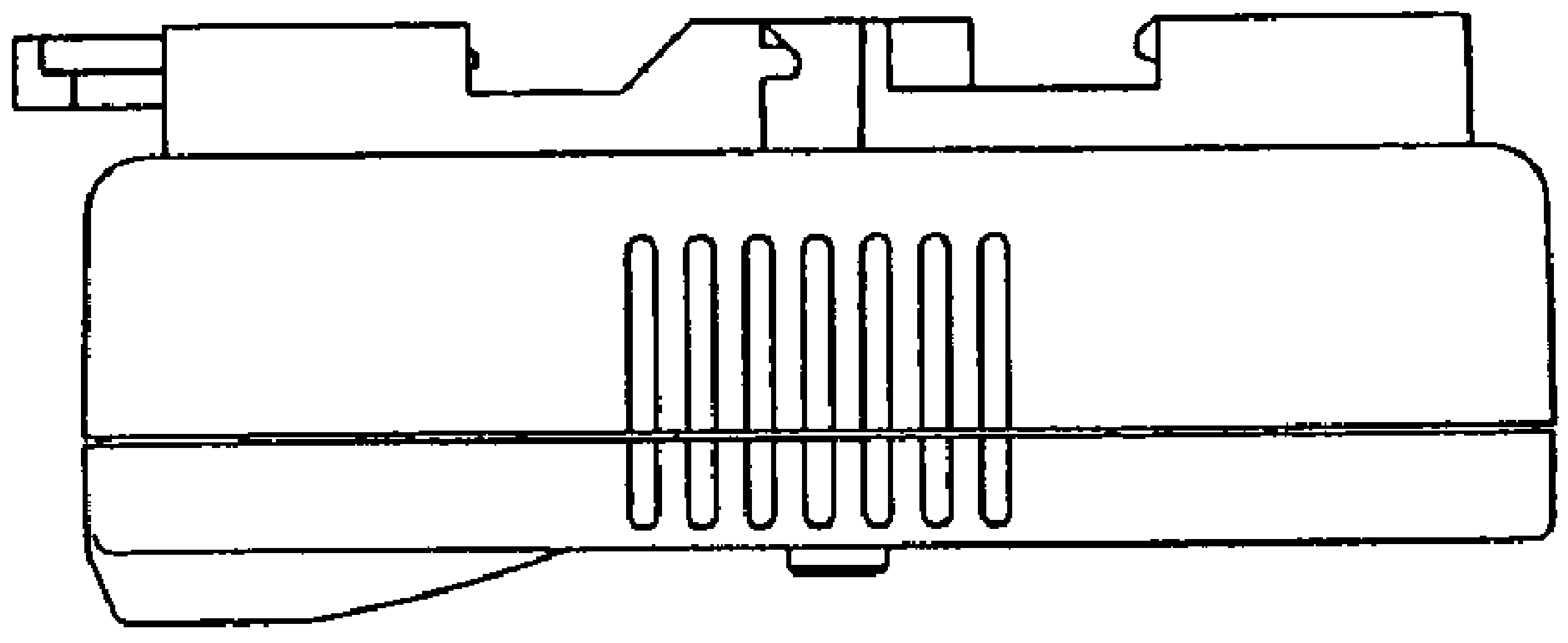


Figure 5

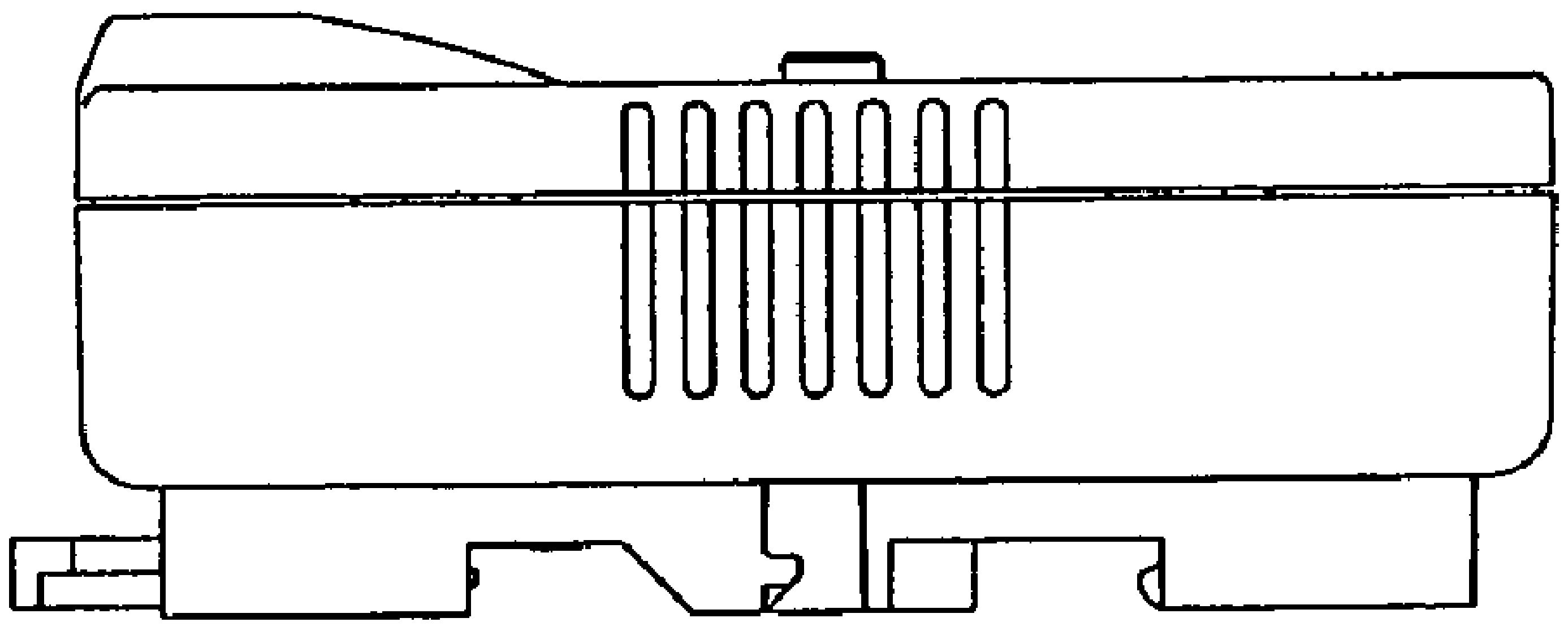
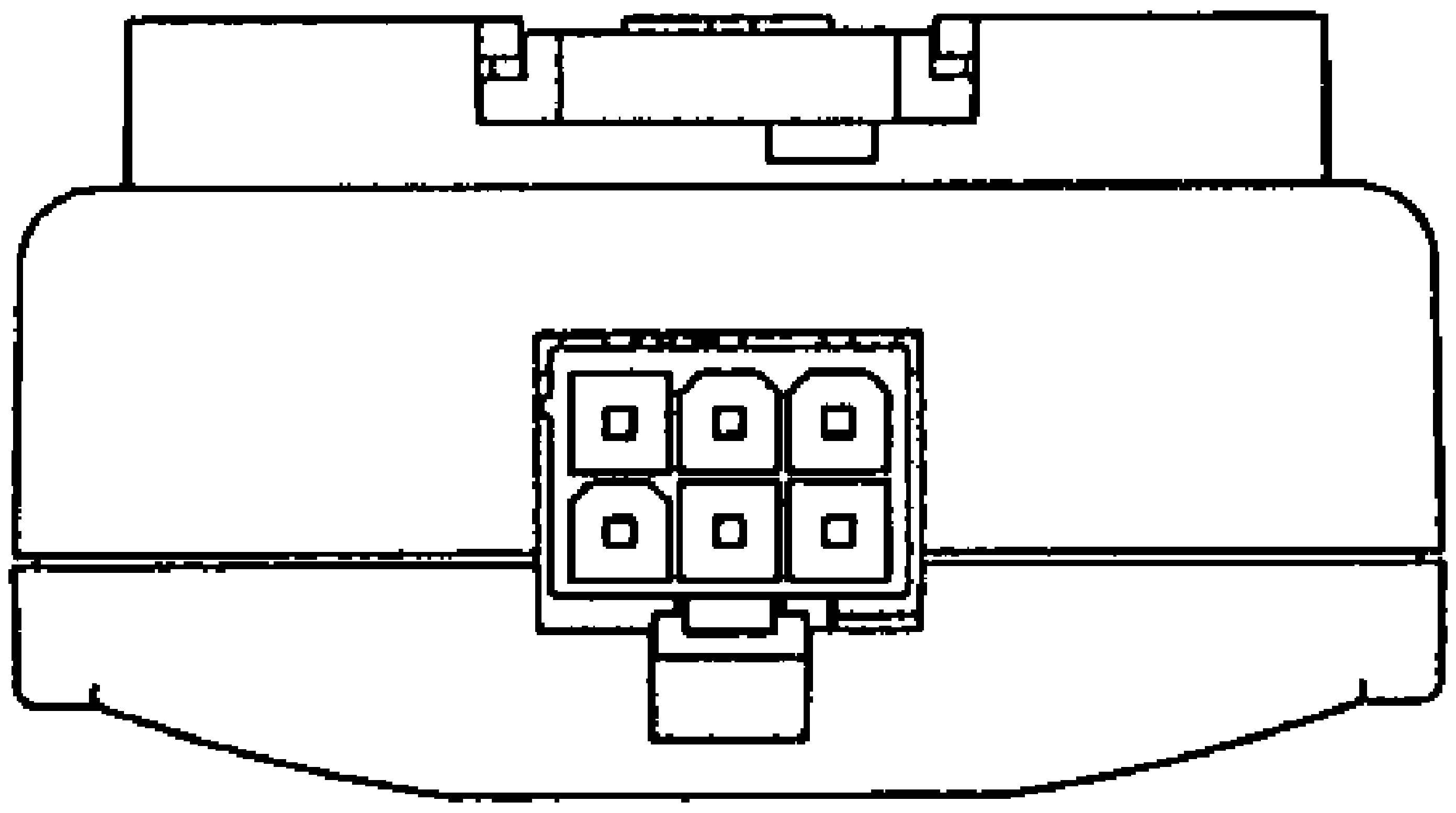


Figure 6

Figure 7



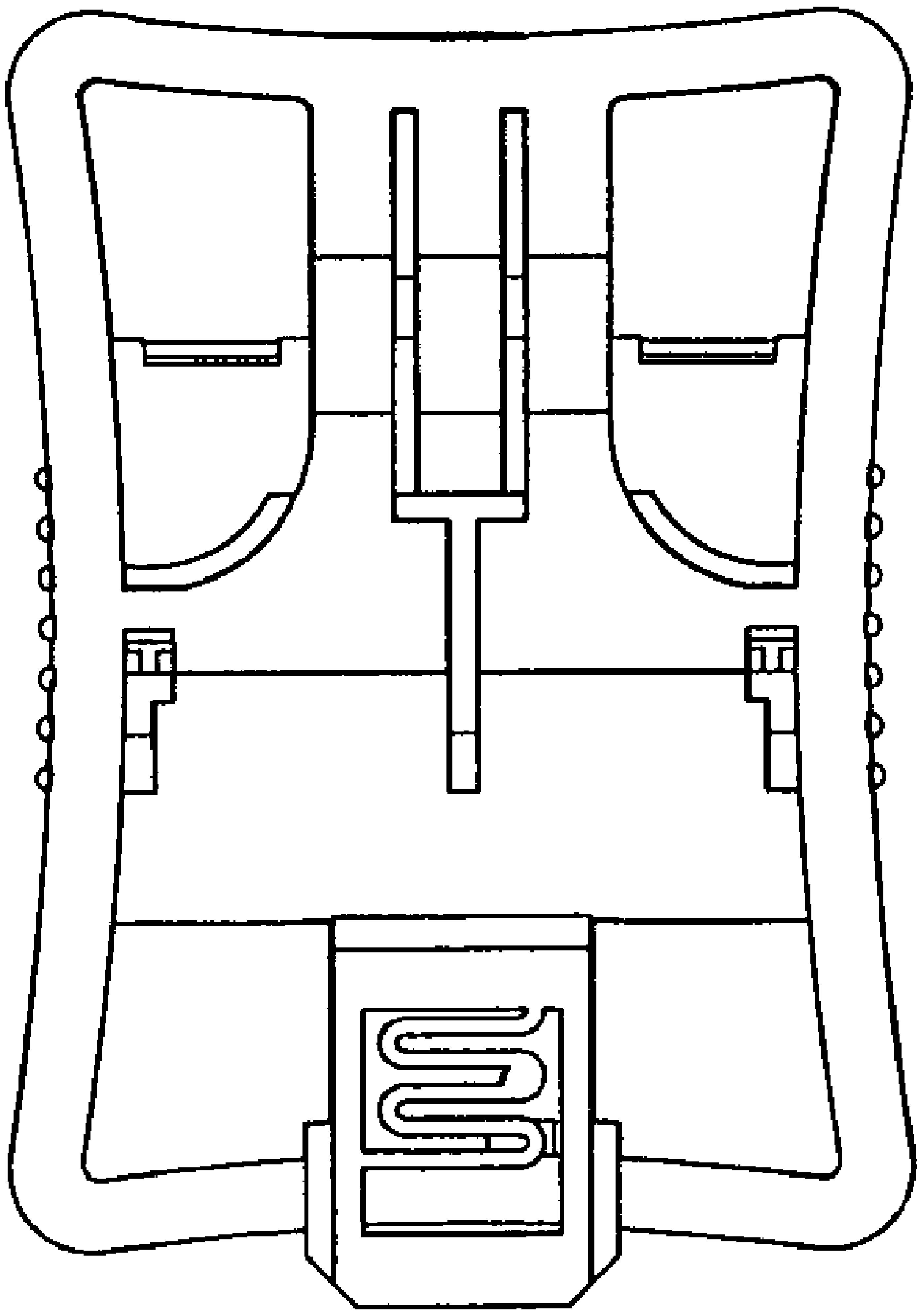


Figure 8